# DISCRETE SEMICONDUCTORS



Product specification Supersedes data of March 1991 1996 Mar 21



# BZV10 to BZV14

### FEATURES

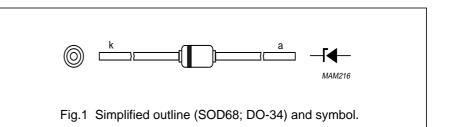
- Temperature compensated
- Reference voltage range: 5.9 to 6.5 V (typ. 6.2 V)
- Low temperature coefficient range: max. 0.0005 to 0.01 %/K.

### APPLICATION

• Voltage reference sources in measuring instruments such as digital voltmeters.

#### DESCRIPTION

Voltage reference diode in a hermetically-sealed SOD68 (DO-34) glass package.



## LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
IZ	working current		_	50	mA
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 50 °C	_	400	mW
T <sub>stg</sub>	storage temperature		-65	+200	°C
Tj	junction temperature		_	200	°C
T <sub>amb</sub>	operating ambient temperature		0	+70	°C

## BZV10 to BZV14

### ELECTRICAL CHARACTERISTICS

 $T_{amb}$  = 25 °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V <sub>ref</sub>	reference voltage	I <sub>Z</sub> =2 mA	5.9	6.2	6.5	V
$ \Delta V_{ref} $	reference voltage excursion	$I_Z = 2$ mA; test points for				
	BZV10	T <sub>amb</sub> : 0; +25; +70 °C;	-	-	46	mV
	BZV11	notes 1 and 2	_	_	23	mV
	BZV12		_	-	9	mV
	BZV13		-	-	4.6	mV
	BZV14		-	_	2.3	mV
S <sub>Z</sub>	temperature coefficient	$I_Z = 2 \text{ mA: see Fig.2;}$				
	BZV10	notes 1 and 2	-	—	0.01	%/K
	BZV11		-	-	0.005	%/K
	BZV12		-	-	0.002	%/K
	BZV13		—	-	0.001	%/K
	BZV14		_	_	0.0005	%/K
r <sub>dif</sub>	differential resistance	I <sub>Z</sub> = 2 mA; see Fig.3	_	20	50	Ω

#### Notes

- 1. The quoted values of  $\Delta V_{ref}$  are based on a constant current  $I_Z$ . Two factors can cause  $\Delta V_{ref}$  to change, namely the differential resistance  $r_{dif}$  and the temperature coefficient  $S_Z$ .
  - a) As the max.  $r_{dif}$  of the device can be 50  $\Omega$ , a change of 0.01 mA in the current through the reference diode will result in a  $\Delta V_{ref}$  of 0.01 mA  $\times$  50  $\Omega$  = 0.5 mV. This level of  $\Delta V_{ref}$  is not significant on a BZV10 ( $\Delta V_{ref}$  < 46 mV), it is however very significant on a BZV14 ( $\Delta V_{ref}$  < 2.3 mV).
  - b) The temperature coefficient of the reference voltage S<sub>Z</sub> is a function of I<sub>Z</sub>. Reference diodes are classified at the specified test current, and the S<sub>Z</sub> of the reference diode will be different at different levels of I<sub>Z</sub>. The absolute value of I<sub>Z</sub> is important, however, the stability of I<sub>Z</sub>, once the level has been set, is far more significant. This applies particularly to the BZV13 and BZV14. The effect of the stability of I<sub>Z</sub> on S<sub>Z</sub> is shown in Fig.2.
- 2. All reference diodes are characterized by the 'box method'. This guarantees a maximum voltage excursion (ΔV<sub>ref</sub>) over the specified temperature range, at the specified test current (I<sub>Z</sub>), verified by tests at indicated temperature points within the range. V<sub>Z</sub> is measured and recorded at each temperature specified. The ΔV<sub>ref</sub> between the highest and lowest values must not exceed the maximum ΔV<sub>ref</sub> given. Therefore the temperature coefficient is only given as

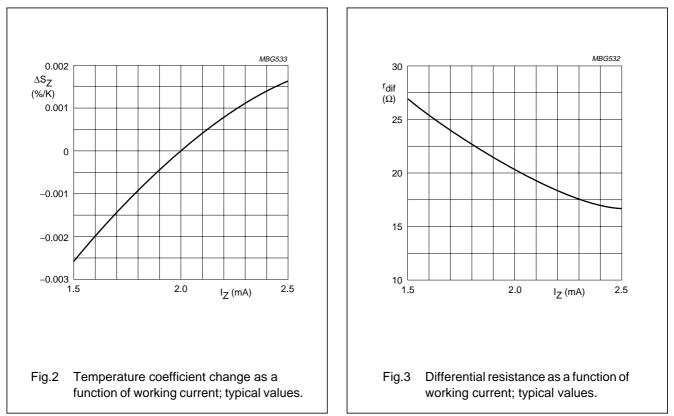
a reference. It may be derived from: 
$$S_{Z} = \frac{V_{ref1} - V_{ref2}}{T_{amb2} - T_{amb1}} \times \frac{100}{V_{ref nom}} %/K$$

#### THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R <sub>th j-tp</sub>	thermal resistance from junction to tie-point	8 mm from the body	300	K/W
R <sub>th j-a</sub>	thermal resistance from junction to ambient	lead length 10 mm	375	K/W

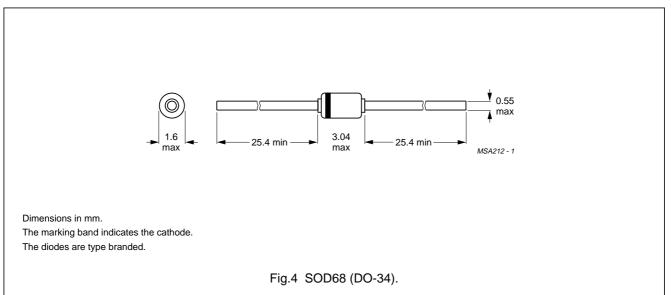
# BZV10 to BZV14

### **GRAPHICAL DATA**



## BZV10 to BZV14

#### PACKAGE OUTLINE



#### DEFINITIONS

Data Sheet Status	
Objective specification	This data sheet contains target or goal specifications for product development.
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.
Product specification	This data sheet contains final product specifications.
Limiting values	
more of the limiting values of the device at these or at	accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or may cause permanent damage to the device. These are stress ratings only and operation any other conditions above those given in the Characteristics sections of the specification limiting values for extended periods may effect device reliability.
is not implied. Exposure to	limiting values for extended periods may affect device reliability.
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#### LIFE SUPPORT APPLICATIONS

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